

10/562751
IAP20 Rec'd PCT/PTO 28 DEC 2005
PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

EXPRESS MAIL NO. EV351242392US

Appl No.	: N/A	Confirmation No.
Applicant	: Akio Ishikawa	
Filed	: December 28, 2005	
Title	: PATTERN COMPARISON INSPECTION METHOD AND PATTERN COMPARISON INSPECTION APPARATUS (AS AMENDED)	
TC/A.U.	: N/A	
Examiner	: N/A	
Docket No.	: 56799/A400	
Customer No.	: 23363	

PRELIMINARY AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Post Office Box 7068
Pasadena, CA 91109-7068
December 28, 2005

Commissioner:

Prior to examination, please amend the above-identified application as follows:

Amendments to the Specification begin on page 2 of this paper.

Remarks/Arguments begin on page 3 of this paper.